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(54) **SILICON CARBIDE SEMICONDUCTOR DEVICE AND METHOD FOR PRODUCING THE SAME**

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See application file for complete search history.

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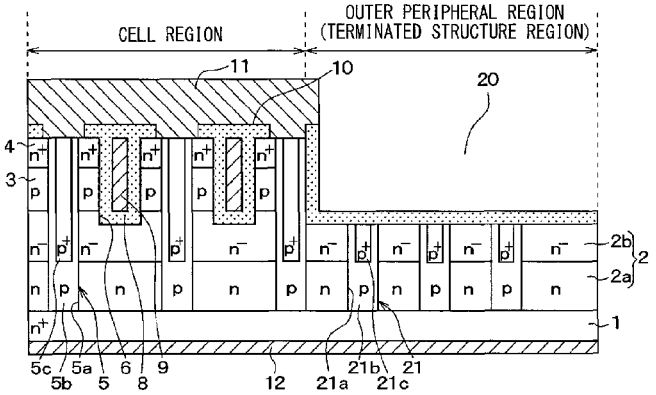
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